Notice of R ferenc s Cited Application/Control No. 09/449,625 Examiner Shun Lee Applicant(s)/Patent Under Reexamination OGAWA, HIROSHI Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,728,583 A	03-1988	Yamazaki et al.	428/690
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